



IFW

Docket No.: M4065.0167/P167-A
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Kevin G. Donohoe et al.

Application No.: 10/779,843

Confirmation No.: 9432

Filed: February 18, 2004

Art Unit: 1765

For: ASPECT RATIO-CONTROLLED ETCH
SELECTIVITY USING TIME MODULATED
DC BIAS VOLTAGE

Examiner: Not Yet Assigned

STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. Please advise us of when we might expect to receive an Office Action from the Patent and Trademark Office.

Dated: April 18, 2005

Respectfully submitted,

By

Thomas J. D'Amico

Registration No.: 28,371

DICKSTEIN SHAPIRO MORIN & OSHINSKY
LLP

2101 L Street NW

Washington, DC 20037-1526

(202) 785-9700

Attorney for Applicant